

**AMENDMENTS TO THE CLAIMS**

1. (Currently Amended) A method of testing a memory die, comprising:  
  
    testing said memory die; and  
  
    ~~storing at least a partial memory cell address on said die as a result of said~~  
  
    ~~testing act~~ storing in said memory die at least a partial address of any defective  
  
    memory cell found during said testing, wherein said storing replaces any  
  
    previously stored address or partial address, said at least a partial address  
  
    corresponding to a memory cell having failed said testing ~~[[act]]~~,  
  
    wherein said testing and storing ~~[[acts]]~~ are performed outside of a  
  
    production facility of said die.
2. (Currently Amended) The method in claim 1, wherein said testing ~~[[act]]~~  
  
comprises testing said die while said die is part of an electronic system.
3. (Currently Amended) The method in claim 2, wherein said testing ~~[[act]]~~  
  
comprises testing said die while said electronic system is in a power management  
  
mode.
4. (Currently Amended) The method in claim 2, wherein said testing ~~[[act]]~~  
  
comprises testing said die while said die is part of a computer system.

5. (Currently Amended) The method in claim 2, wherein said testing [[act]] comprises testing said die while said die is part of a telephone system.

6. (Currently Amended) The method in claim 5, wherein said testing [[act]] comprises testing said die while said die is part of a cellular telephone system.

7-63. (Canceled)

64. (Currently Amended) A method of testing a memory die, comprising:

testing said memory die; and

~~storing at least a partial memory cell address on said die as a result of said testing act~~ storing in said memory die at least a partial address of any defective memory cell found during said testing, wherein said storing replaces any previously stored address or partial address, said at least a partial address corresponding to a memory cell having failed said testing [[act]],

wherein said testing and storing [[acts]] are performed in [[the]] a field.

65. (Currently Amended) A method of testing a memory die, comprising:

testing said memory die; and

~~storing at least a partial memory cell address on said die as a result~~  
~~of said testing act~~ storing in said memory die at least a partial address of  
any defective memory cell found during said testing, wherein said storing  
replaces any previously stored address or partial address, said at least a  
partial address corresponding to a memory cell having failed said testing  
[[act]],

wherein said testing and storing [[acts]] are performed when said  
die is part of a processing system.

66. (New) The method of claim 1, wherein said storing in a register at least a  
partial address of any defective memory cell comprises storing a column address of the  
defective memory cell.

67. (New) The method of claim 1, wherein said storing in a register at least a  
partial address of any defective memory cell comprises storing a row address of the  
defective memory cell.